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	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/709,890	LIN ET AL.
•	Examiner	Art Unit
	Wen-Ying P. Chen	2871

SEARCHED				
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INTERFERENCE SEARCHED				
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Key word search in US- PGPUB,USPAT,USOCR,EPO,JPO,D ERWENT,IBM_TDB databases in EAST: see search history printout	9/22/2005	WPC (LPL
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